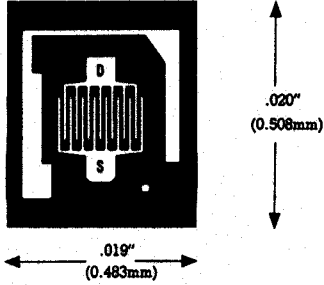


CHIP NUMBER
FN71.1



Die Size: 19 x 20 (mils)
 0.483 x 0.508(mm)
 3 x 3 (mils)
 Pad Size: 0.076 x 0.076(mm)
 GATE-SUBSTRATE

CONTACT METALLIZATION

Top Contact: > 12,000
 Å Aluminum

Backside Contact: 3,000 Å Gold

ASSEMBLY RECOMMENDATIONS

It is advisable that:

- a) the die be eutectically mounted with gold silicon preform 98/2%.
- b) 1 mil (0.0254mm) aluminum wire be ultrasonically attached to the top contact.

TYPICAL ELECTRICAL CHARACTERISTICS

PARAMETER	MIN.	TYP	MAX.	UNIT	TEST CONDITIONS
BVGSS	-20	-30	-40	V	$V_{DS} = 0, I_G = 1\mu A$
IDSS	10	30	60	mA	$V_{DS} = 10V, I_G = 1\mu A$
g_{fs}		15	20	mmho	$V_{DS} = 10V, I_D = 10mA, f = 1KHz$
IGSS		40	150	pA	$V_{GS} = -15V, V_{DS} = 0$
VGS	-1	-5	-8V	V	$V_D = 10V, I_D = 1nA$
NF			1.5	dB	$V_{DS} = 10V, I_D = 10mA, f = 100MHz$
C_{gd}		1.8	2.5	pF	$V_{DS} = 10V, I_D = 10mA, f = 1MHz$
C_{gs}		4.0	5.0	pF	$V_{DS} = 10V, I_D = 10mA, f = 1MHz$
\dot{e}_n		10	20	nV/ \sqrt{Hz}	$V_{DS} = 10V, I_D = 10mA, f = 100Hz$

TYPICAL DEVICE TYPES: U308 - U311

CHIP TYPE FN71.1

